


<b>Search Notes</b>  	<b>Application/Control No.</b>  10632082	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Han, Jason M	<b>Art Unit</b>  2875

SEARCHED			
Class	Subclass	Date	Examiner
362	217-225, 260, 646	6/4/2008	JMH
349	58, 70-71	6/4/2008	JMH
439	56, 235	6/4/2008	JMH

SEARCH NOTES		
Search Notes	Date	Examiner
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	9/26/2006	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	11/8/2007	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	6/4/2008	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	10/30/2008	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	4/30/2009	JMH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	EAST (US-PGPUB) - See Printout	4/30/2009	JMH

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